ON Semiconductor

INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION #20731

Generic Copy

Issue Date: 13-Jan-2015

TITLE: Release of an additional tester platform (T2000) for the NCV7707DQR2G (currently tested on Micro Flex tester platform)

PROPOSED FIRST SHIP DATE: 20-May-2015 or earlier upon approval

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor Sales Office, your customer quality interface or Xavier Van Esch (xavier.vanesch@onsemi.com)

NOTIFICATION TYPE:

Initial Product/Process Change Notification (IPCN)

First change notification sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.

The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN).

This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change.

DESCRIPTION AND PURPOSE:

This is to announce the release of T2000 tester platform for Final Test and QC to improve tester capacity balancing and loading.

Qualification data:

QC ambient correlation data between the source tester (Micro Flex) and the target tester (T2000) will be provided in a separate qualification report together with the Final PCN.

The correlation procedure will be used, like done as in previous PCN's covering the release of additional tester platforms

- 2 correlation units will be serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test will be done at room temperature, using the QC program.

- Then, the same correlation units will be used to gather data on target tester T2000.
- The same datalogging procedure used for Micro Flex will be followed for T2000.

- Full parametric correlation will be performed and for every test the shift will be evaluated as follows:

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Δmean = abs(mean(ref)-mean(qual))
Δsigma = 0 **if sigma(qual) < sigma(ref)**
Δsigma = sigma(qual) – sigma(ref) **if sigma(qual) > sigma(ref)**

shift = Δmean + 4 * Δsigma

If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test,
else correlation is NOK for this test

Any parameter that is NOK is independently analyzed and explained.

- 10 Rejects from Hot and 10 rejects from Cold will be serialized and datalogged on Micro Flex. The same devices will be tested on T2000. Results should match, deviations must be explained.

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical Performance will continue to meet specifications.

List of Affected Customer Specific Parts:

ON Semi Part Number
NCV7707DQR2G